

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Seok-Hyun Yun

Inventor:

Appln. No.:

10/577,562

Filed:

April 27, 2006

Title:

METHOD AND APPARATUS FOR PERFORMING

OPTICAL IMAGING USING FREQUENCY-DOMAIN

INTERFEROMETRY

Examiner:

To be assigned

Group Art

2859

Unit:

REOUEST FOR CORRECTION OF FILING RECEIPT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 I hereby certify that this document is being deposited with the United States Postal Service addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 8th day of August 2006.

(Signature)

Sir:

Applicant hereby requests correction in the Filing Receipt. The inventor's last name was not included. In particular, the name of the inventor's last name should be identified as BRETT EUGENE BOUMA and not "BRETT EUGENE". In addition, under the Foreign Application category, nothing should be listed, and Domestic Priority data category should be the application number as "60/514,769" (incorrectly provided in the "Foreign Application" category) not 60514789.

Enclosed herewith is the executed declaration and the first page of International Publication No. WO 2005/047813. Also enclosed is the marked-up filing receipt.

Please forward a corrected filing receipt to reflect the last name of the inventor and the correct priority application number to the undersigned as soon as possible.

Respectfully submitted,

Date: August 8, 2006

By:

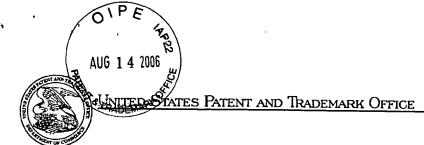
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Enclosures

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10/577,562	04/27/2006	2859	6850	036179US247538700030	20	95	14	

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30873 DORSEY & WHITNEY LLP INTELLECTUAL PROPERTY DEPARTMENT 250 PARK AVENUE NEW YORK, NY 10177

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Receipt is acknowledged of this regular Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. If an error is noted on this Filing Receipt, please mail to the Commissioner for Patents P.O. Box 1450 Alexandria Va 22313-1450. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the USPTO processes the reply to the Notice, the USPTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).

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Power of Attorney: The patent practitioners associated with Customer Number 30873.

Domestic Priority data as claimed by applicant

This application is a 371 of PCT/US04/29148 09/08/2004

Foreign Applications

UNITED STATES OF AMERICA 60514789 10/27/2003

If Required, Foreign Filing License Granted: 07/25/2006

The country code and number of your priority application, to be used for filing abroad under the Paris Convention, is US10/577,562

Projected Publication Date: 11/02/2006

Non-Publication Request: No

Early Publication Request: No

Title

Method and apparatus for performing optical imaging using frequency-domain interferometry

Preliminary Class

033

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27 October 2003 (27.10.2003)

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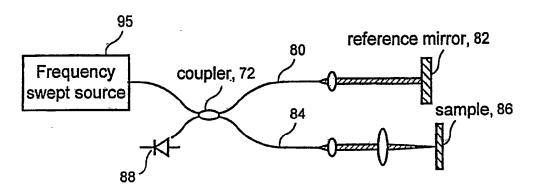
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[Continued on next page]

(54) Title: METHOD AND APPARATUS FOR PERFORMING OPTICAL IMAGING USING FREQUENCY-DOMAIN INTER-**FEROMETRY**



047813 (57) Abstract: An apparatus and method are provided. In particular, at least one first electro-magnetic radiation may be provided to a sample and at least one second electro-magnetic radiation can be provided to a non-reflective reference. A frequency of the first and/or second radiations varies over time. An interference is detected between at least one third radiation associated with the first radiation and at least one fourth radiation associated with the second radiation. Alternatively, the first electro-magnetic radiation and/or second electro-magnetic radiation have a spectrum which changes over time. The spectrum may contain multiple frequencies at a particular time. In addition, it is possible to detect the interference signal between the third radiation and the fourth radiation in a first polarization state. Further, it may be preferable to detect a further interference signal between the third and fourth radiations in a second polarization state which is different from the first polarization state. The first and/or second electro-magnetic radiations may have a spectrum whose mean frequency changes substantially continuously over time at a tuning speed that is greater than 100 Tera Hertz per millisecond.